

Search Notes



Application/Control No.

10/803,999

Examiner

Sin J. Lee

Applicant(s)/Patent under
Reexamination

TAKAHASHI ET AL.

Art Unit

1752

SEARCHED

Class	Subclass	Date	Examiner
430	271.1	5-29 -05	STL
↓	278.1	↓	↓
↓	270.1	↓	↓
↓	944	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR